

FLC157XP

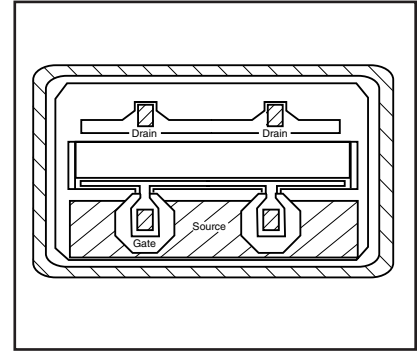
GaAs FET & HEMT Chips

FEATURES

- High Output Power: $P_{1dB} = 31.5\text{dBm}$ (Typ.)
- High Gain: $G_{1dB} = 6.0\text{dB}$ (Typ.)
- High PAE: $\eta_{add} = 29.5\%$ (Typ.)
- Proven Reliability

DESCRIPTION

The FLC157XP chip is a power GaAs FET that is designed for general purpose applications in the C-Band frequency range as it provides superior power, gain, and efficiency.



Fujitsu's stringent Quality Assurance Program assures the highest reliability and consistent performance.

ABSOLUTE MAXIMUM RATING (Ambient Temperature $T_a=25^\circ\text{C}$)

| Item | Symbol | Condition | Rating | Unit |
|-------------------------|-----------|--------------------------|-------------|------------------|
| Drain-Source Voltage | V_{DS} | | 15 | V |
| Gate-Source Voltage | V_{GS} | | -5 | V |
| Total Power Dissipation | P_{tot} | $T_c = 25^\circ\text{C}$ | 8.3 | W |
| Storage Temperature | T_{stg} | | -65 to +175 | $^\circ\text{C}$ |
| Channel Temperature | T_{ch} | | 175 | $^\circ\text{C}$ |

Fujitsu recommends the following conditions for the reliable operation of GaAs FETs:

1. The drain-source operating voltage (V_{DS}) should not exceed 10 volts.
2. The forward and reverse gate currents should not exceed 9.6 and -1.0 mA respectively with gate resistance of 200Ω .
3. The operating channel temperature (T_{ch}) should not exceed 145°C .

ELECTRICAL CHARACTERISTICS (Ambient Temperature $T_a=25^\circ\text{C}$)

| Item | Symbol | Test Conditions | Limit | | | Unit |
|--|--------------|---|-------|------|------|---------------------------|
| | | | Min. | Typ. | Max. | |
| Saturated Drain Current | I_{DSS} | $V_{DS} = 5\text{V}, V_{GS} = 0\text{V}$ | - | 600 | 900 | mA |
| Transconductance | g_m | $V_{DS} = 5\text{V}, I_{DS} = 400\text{mA}$ | 150 | 300 | - | mS |
| Pinch-off Voltage | V_p | $V_{DS} = 5\text{V}, I_{DS} = 30\text{mA}$ | -1.0 | -2.0 | -3.5 | V |
| Gate Source Breakdown Voltage | V_{GSO} | $I_{GS} = -30\mu\text{A}$ | -5 | - | - | V |
| Output Power at 1dB Gain Compression Point | P_{1dB} | $V_{DS} = 10\text{V}$ $I_{DS} \approx 0.6I_{DSS}$ $f = 8\text{GHz}$ | 30.5 | 31.5 | - | dBm |
| Power Gain at 1dB Gain Compression Point | G_{1dB} | | 5.0 | 6.0 | - | dB |
| Power-added Efficiency | η_{add} | | - | 29.5 | - | % |
| Thermal Resistance | R_{th} | Channel to Case | - | 15 | 18 | $^\circ\text{C}/\text{W}$ |

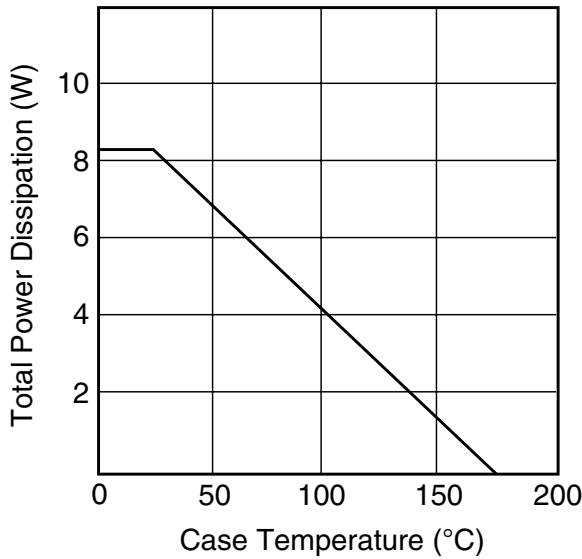
Note: RF parameter sample size 10pcs. criteria (accept/reject)=(2/3)

The chip must be enclosed in a hermetically sealed environment for optimum performance and reliability.

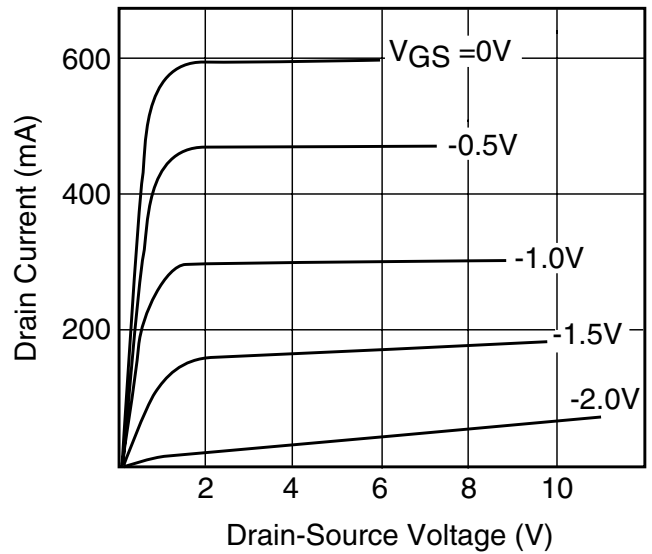
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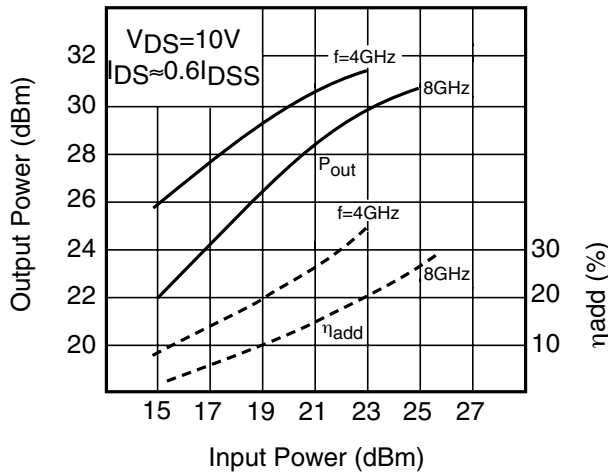
POWER DERATING CURVE



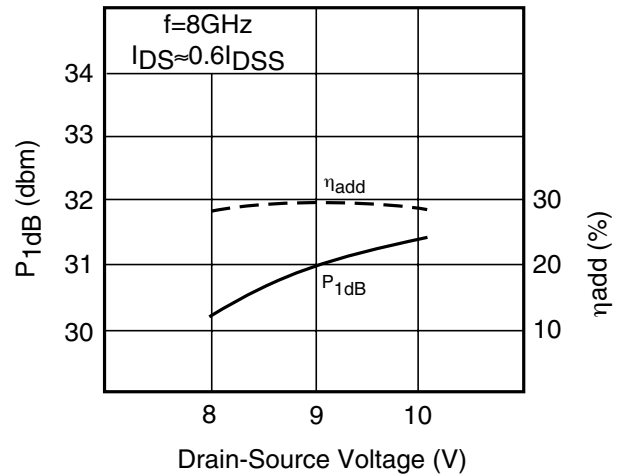
DRAIN CURRENT vs. DRAIN-SOURCE VOLTAGE



OUTPUT POWER vs. INPUT POWER



P_{1dB} & η_{add} vs. V_{DS}



S-PARAMETERS

$V_{DS} = 10V, I_{DS} = 400mA$

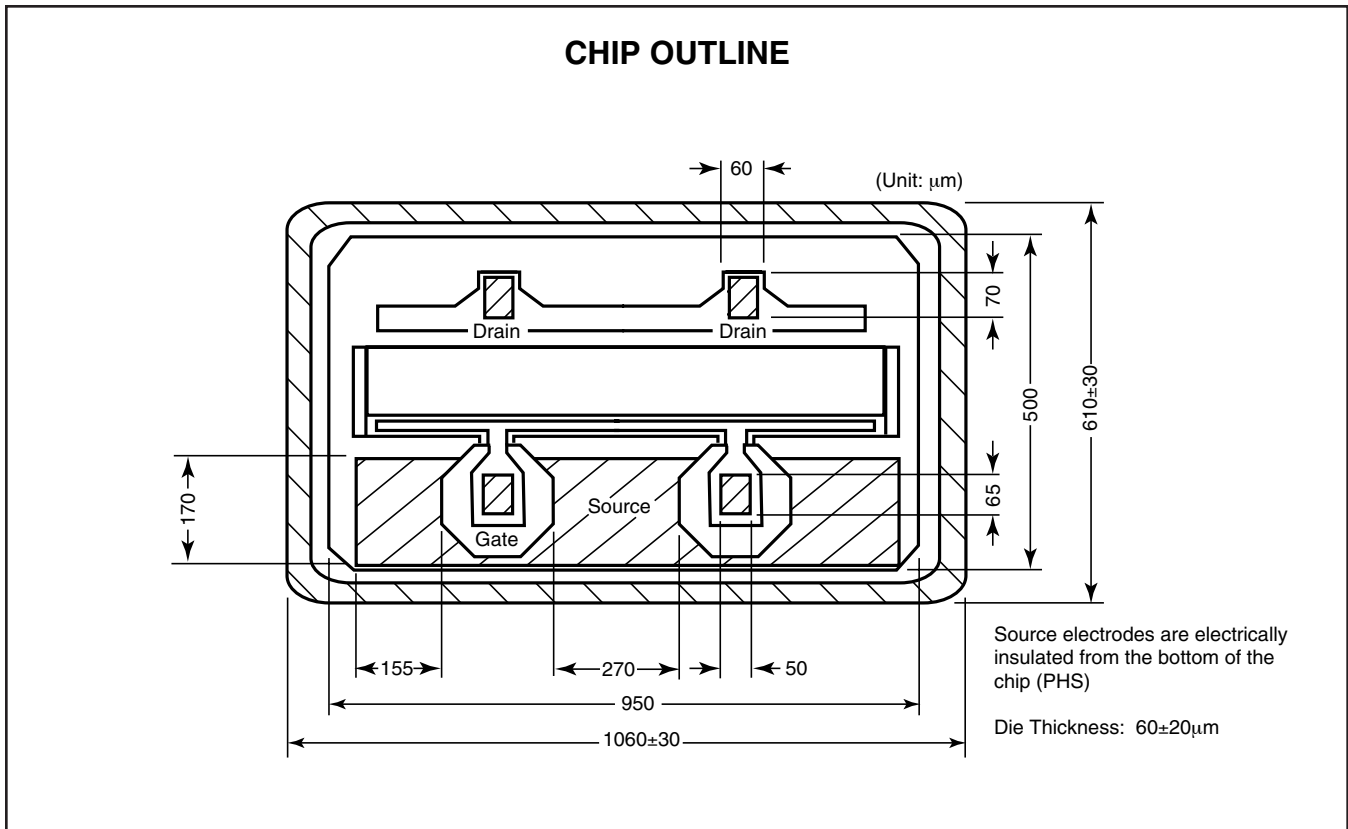
| FREQUENCY (MHZ) | S11 | | S21 | | S12 | | S22 | |
|--------------------|------|--------|--------|-------|------|------|------|--------|
| | MAG | ANG | MAG | ANG | MAG | ANG | MAG | ANG |
| 100 | .993 | -25.9 | 15.864 | 165.0 | .013 | 76.4 | .185 | -39.7 |
| 500 | .918 | -98.4 | 10.322 | 123.1 | .041 | 40.2 | .293 | -115.6 |
| 1000 | .881 | -134.6 | 6.162 | 100.0 | .049 | 24.2 | .337 | -139.9 |
| 2000 | .868 | -159.5 | 3.250 | 77.3 | .051 | 15.8 | .375 | -150.6 |
| 3000 | .868 | -169.8 | 2.178 | 61.7 | .051 | 14.8 | .413 | -152.6 |
| 4000 | .871 | -176.3 | 1.625 | 48.3 | .050 | 16.3 | .456 | -153.5 |
| 5000 | .875 | 178.9 | 1.284 | 36.0 | .050 | 19.3 | .503 | -154.9 |
| 6000 | .881 | 174.8 | 1.051 | 24.6 | .050 | 23.3 | .550 | -156.8 |
| 7000 | .886 | 171.2 | .878 | 13.8 | .052 | 27.9 | .597 | -159.3 |
| 8000 | .892 | 167.8 | .743 | 3.7 | .054 | 32.5 | .641 | -162.2 |
| 9000 | .897 | 164.6 | .633 | -5.8 | .057 | 36.7 | .682 | -165.4 |
| 10000 | .903 | 161.5 | .541 | -14.6 | .061 | 40.2 | .720 | -168.7 |
| 11000 | .907 | 158.4 | .462 | -22.9 | .067 | 42.8 | .753 | -172.1 |
| 12000 | .912 | 155.5 | .393 | -30.5 | .072 | 44.6 | .783 | -175.6 |

NOTE:* The data includes bonding wires.

n: number of wires Gate n=2 (0.3mm length, 25µm Dia Au wire)
 Drain n=2 (0.3mm length, 25µm Dia Au wire)
 Source n=4 (0.3mm length, 25µm Dia Au wire)

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